

## 60V, 12A Dual N-CHANNEL POWER MOSFET

### GENERAL DESCRIPTION

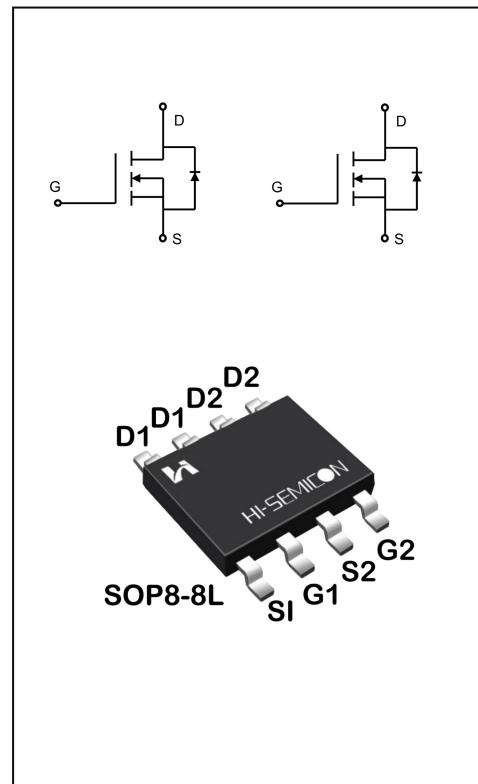
The SFS6012T2 uses advanced trench technology and design to provide excellent  $R_{DS(on)}$  with low Junction capacitance. It can be used in a wide variety applications.

### Features

- ◆  $V_{DS}=60V, I_D=12A$
- ◆  $R_{DS(on)}$   
TYP:  $14.5m\Omega @ V_{GS}=10V$   
TYP:  $19.2m\Omega @ V_{GS}=4.5V$

### Applications

- ◆ Power factor correction (PFC)
- ◆ Switched mode power supplies (SMPS)
- ◆ Uninterruptible power supply (UPS)
- ◆ LED lighting power



### ORDERING INFORMATION

Part No.	Package	Marking	Material	Packing
SFS6012T2	SOP8-8L	SFS6012T2	Pb Free	Reel

**ABSOLUTE MAXIMUM RATINGS (T<sub>J</sub>=25°C unless otherwise noted)**

Characteristics	Symbol	Ratings	Unit
Drain-Source Voltage	V <sub>DS</sub>	60	V
Gate-Source Voltage	V <sub>GS</sub>	±20	V
Drain Current	I <sub>D</sub>	12	A
T <sub>C</sub> = 100°C	I <sub>D</sub>	9.2	
Drain Current Pulsed(Note 1)	I <sub>DM</sub>	48	A
Power Dissipation(T <sub>C</sub> =25°C) -Derate above 25°C	P <sub>D</sub>	1.45	W
Single Pulsed Avalanche Energy (Note 2)	E <sub>AS</sub>	112	mJ
Operation Junction Temperature Range	T <sub>J</sub>	-55~+150	°C
Storage Temperature Range	T <sub>stg</sub>	-55~+150	°C
Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	TL	300	°C

**THERMAL CHARACTERISTICS**

Characteristics	Symbol	MAX	Unit
Thermal Resistance, Junction-to-Case	R <sub>θJC</sub>	31	°C/W
Thermal Resistance, Junction-to-Ambient	R <sub>θJA</sub>	81	°C/W

**ELECTRICAL CHARACTERISTICS**

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
<b>Off Characteristics</b>						
Drain -Source Breakdown Voltage	B <sub>VDSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	60	--	--	V
Drain-Source Leakage Current	I <sub>DS</sub>	V <sub>DS</sub> =60V, V <sub>GS</sub> =0V	--	--	1	uA
Gate-Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =20V, V <sub>DS</sub> =0V	--	--	100	nA
Gate-Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =-20V, V <sub>DS</sub> =0V	--	--	-100	
<b>On Characteristics</b>						
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> =250μA	1.4	1.9	2.5	V
Static Drain- Source On State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =10A	--	14.5	18	mΩ
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =5A	--	19.2	25	
<b>Dynamic Characteristics</b>						
Gate Resistance	R <sub>g</sub>	V <sub>GS</sub> =0V, f=1.0MHZ	1	5	10	Ω
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> =25V V <sub>GS</sub> =0V f=1.0MHZ	--	1720	--	pF
Output Capacitance	C <sub>oss</sub>		--	71	--	
Reverse Transfer Capacitance	C <sub>rss</sub>		--	49	--	
<b>Switching Characteristics</b>						
Turn-on Delay Time	t <sub>d(on)</sub>	V <sub>DD</sub> =30V, V <sub>GS</sub> =10V R <sub>G</sub> =6.7Ω, I <sub>D</sub> =10A (Note 3.4)	--	16.5	--	ns
Turn-on Rise Time	t <sub>r</sub>		--	6.9	--	
Turn-off Delay Time	t <sub>d(off)</sub>		--	36.5	--	
Turn-off Fall Time	t <sub>f</sub>		--	6.7	--	

Total Gate Charge	$Q_g$	$V_{DS}=30V, I_D=10A$ $V_{GS}=10V$ (Note 3.4)	--	32	--	nc
Gate-Source Charge	$Q_{gs}$		--	6.1	--	
Gate-Drain Charge	$Q_{gd}$		--	14.3	--	

## SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Continuous Source Current	$I_s$	Integral Reverse P-N Junction Diode in the MOSFET	--	--	12	A
Pulsed Source Current	$I_{SM}$		--	--	48	
Diode Forward Voltage	$V_{SD}$	$I_s=10A, V_{GS}=0V$	--	0.8	1.2	V
Reverse Recovery Time	$T_{rr}$	$I_F=10A, V_R=15V,$ $dI/dt=100A/\mu s$	--	53	--	ns
Reverse Recovery Charge	$Q_{rr}$		--	62	--	nC

1.Pulse width limited by maximum junction temperature

2. $L=1mH, V_{DD}=30V, V_G=10V, R_G=25\Omega$ , starting  $T_J=25^\circ C$ 3.Pulse Test: Pulse width  $\leq 300\mu s$ , Duty cycle $\leq 2\%$ 

4.Essentially independent of operating temperature

## Typical Performance Characteristics

Figure 1. Output Characteristics

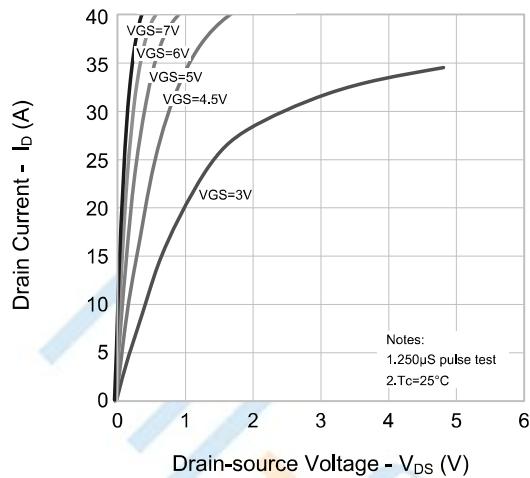


Figure 2. Transfer Characteristics

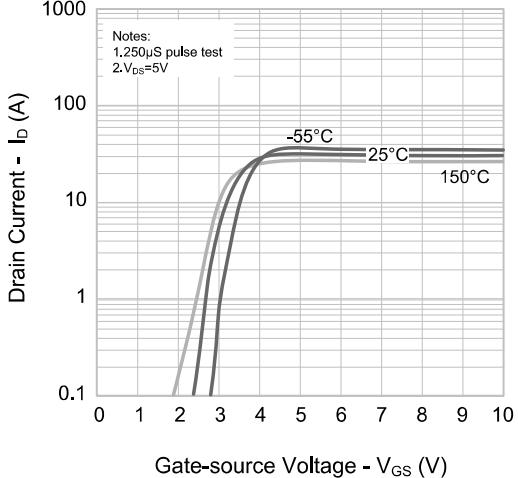


Figure 3. On-resistance vs. Drain Current

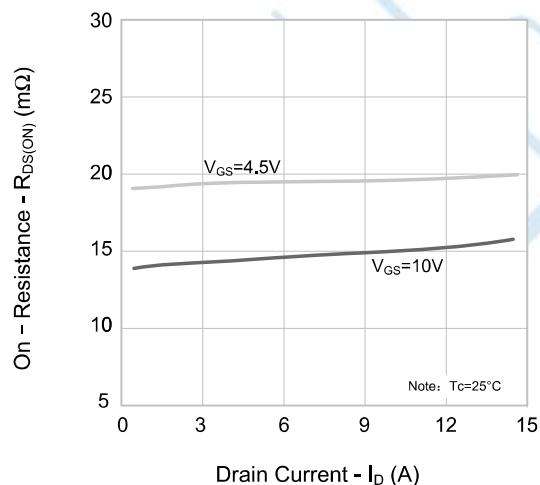


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

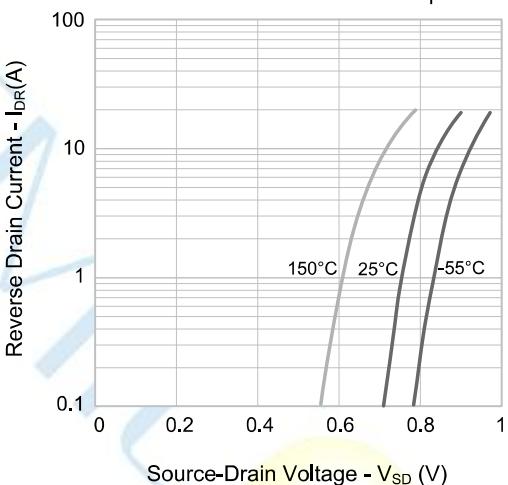


Figure 5. Capacitance Characteristics

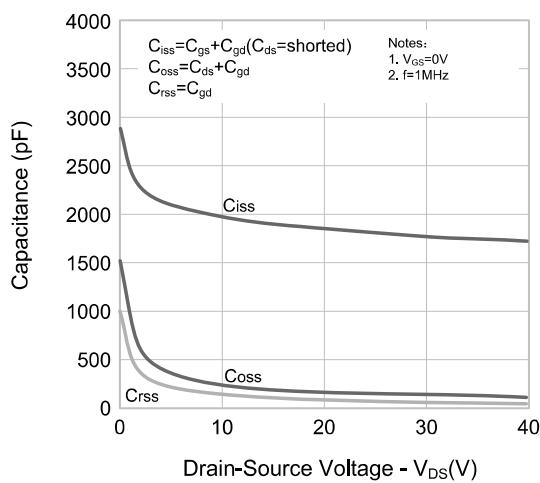
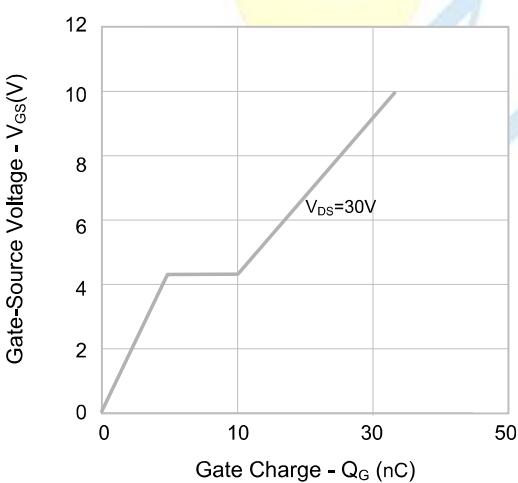


Figure 6. Gate Charge



## Typical Performance Characteristics

Figure 7. Breakdown Voltage vs. Temperature Characteristics

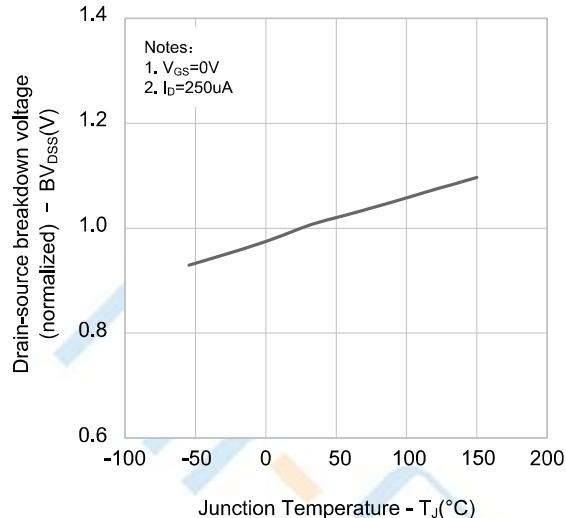


Figure 8. On-resistance vs. Temperature Characteristics

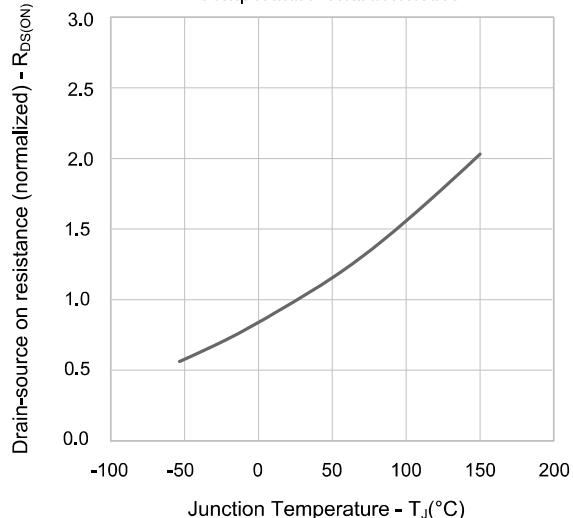
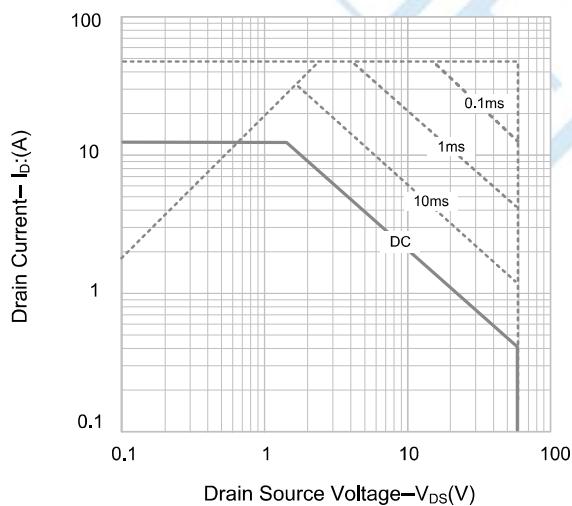
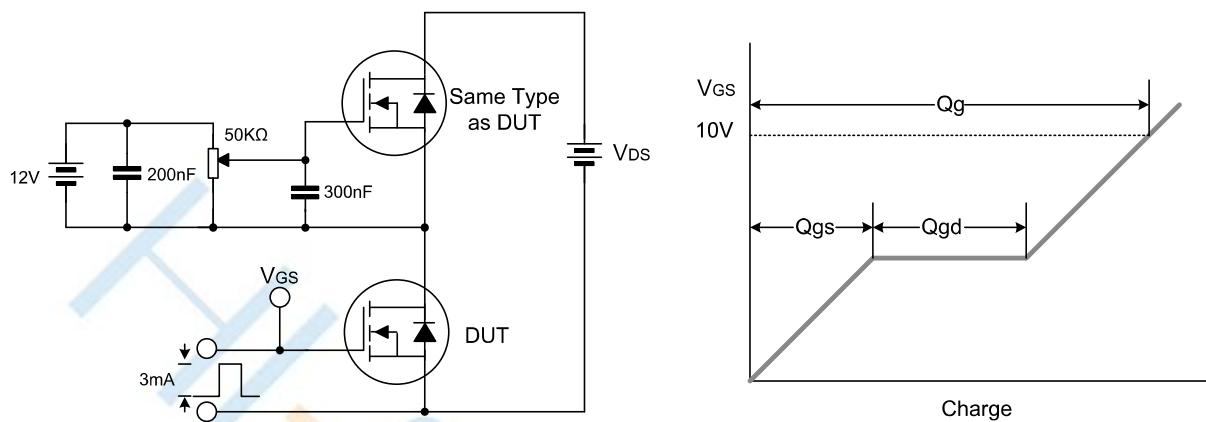


Figure 9. Max. Safe Operating Area

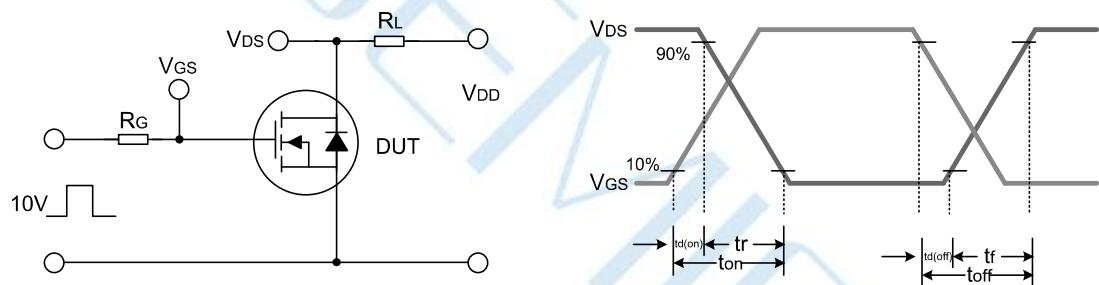


## Test Circuit

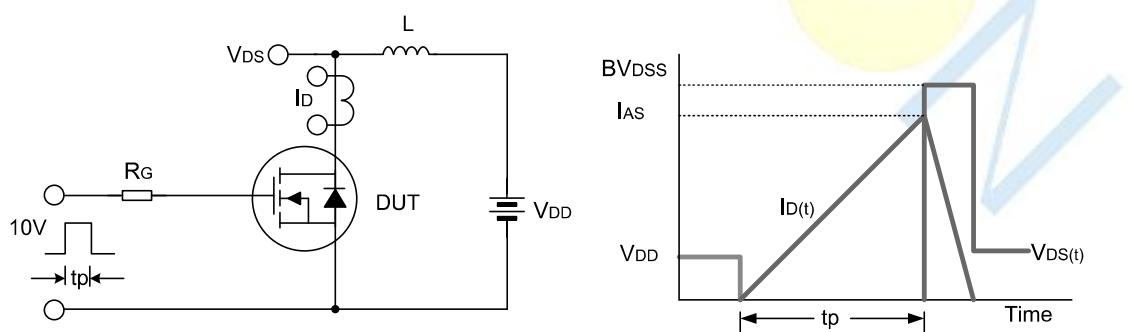
Gate Charge Test Circuit &amp; Waveform



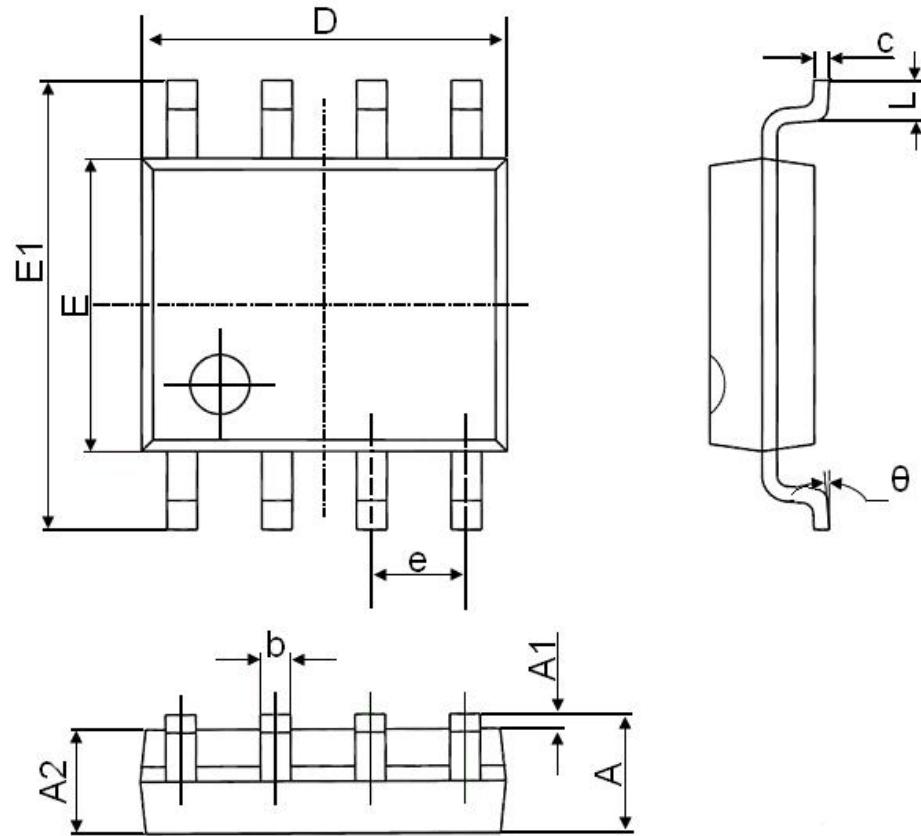
Resistive Switching Test Circuit &amp; Waveform



Unclamped Inductive Switching Test Circuit &amp; Waveform



## Package Dimensions of SOP8-8L



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
A	1.350	1.750	0.053	0.069
A1	0.100	0.250	0.004	0.010
A2	1.350	1.550	0.053	0.061
b	0.330	0.510	0.013	0.020
c	0.170	0.250	0.006	0.010
D	4.700	5.100	0.185	0.200
E	3.800	4.000	0.150	0.157
E1	5.800	6.200	0.228	0.244
e	1.270 (BSC)		0.050 (BSC)	
L	0.400	1.270	0.016	0.050
θ	0°	8°	0°	8°

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